NTAG I²C *plus* Rev. 4.1 — 30 October 2025

Errata

Product identification

The following errata sheet entries are related to NTAG I²C *plus* NT3H2xxx product family and documents deviations from the data sheet ref.[1].

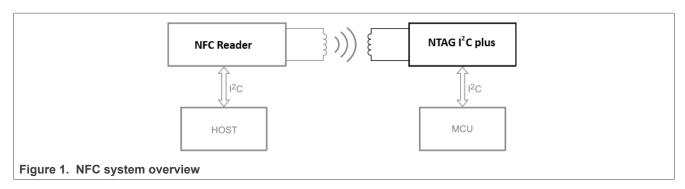


2 I²C Read command treated as I²C Write command and I²C Read/Write payload data not valid

This chapter is intended to clarify specific situations, which could arise in the NXP, focusing on the NFC tag part - NTAG I²C *plus* (Figure 1). For more details, refer to the data sheet.

This chapter describes:

- the occurrences and possible workarounds for events when I²C and RF communications happen simultaneously. These events lead to potential data corruption during reading or writing to NTAG I²C plus EEPROM memory
- general best practices for Host MCU Software design, to achieve a reliable I²C transaction in cases when an RF field interferes at specific timings
- NTAG I²C plus I²C follower address recovery mechanism, if NTAG I²C plus I²C address gets unintentionally reprogrammed



2.1 Issue description

Table 1. Problems summary table

Scenario ID	Short description	Detailed description
1	I ² C Read command treated as I ² C Write command	Section 2.1.1
2	I ² C Read/Write payload data not valid	Section 2.1.2

2.1.1 I²C Read command treated as I²C Write command

2.1.1.1 Scenario description

If RF field toggling (RF-ON/RF-OFF) occurs during I²C READ operation, there is a low probability that an I²C READ operation can be unintentionally turned into treated as I²C WRITE operation by NTAG I²C *plus*.

2.1.1.2 Scenario impact

EEPROM data may be unintentionally overwritten. All EEPROM memory blocks may be affected, listed ones with possible higher impact on application behavior:

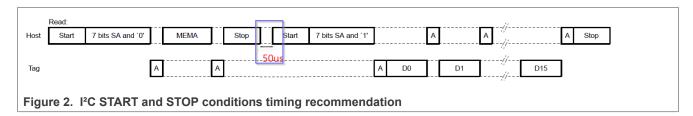
- 1. NTAG I²C plus I²C follower Address (EEPROM Block0)
- 2. Configuration Registers (NTAG I²C *plus* startup behavior)

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2.1.1.3 Recommendations

2.1.1.3.1 I²C START and STOP recommendation

Use the I²C STOP and START symbols, with a wait time of at least 50 µs between STOP and START, instead of using I²C repeated start (no STOP condition).



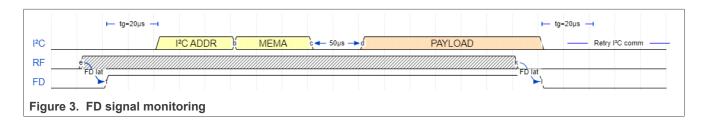
2.1.1.3.2 FD Signal Monitoring

From the MCU Host side, use FD signal to detect whether the RF field has switched ON/OFF during an I²C transaction. If the event is detected, abort and repeat the ongoing I²C transaction.

It is recommended to check FD state:

- before initiating an I²C frame, with a minimum guard time (t_0) of 20 µs before the start of the I²C frame
- 20 µs after the I2C frame's end

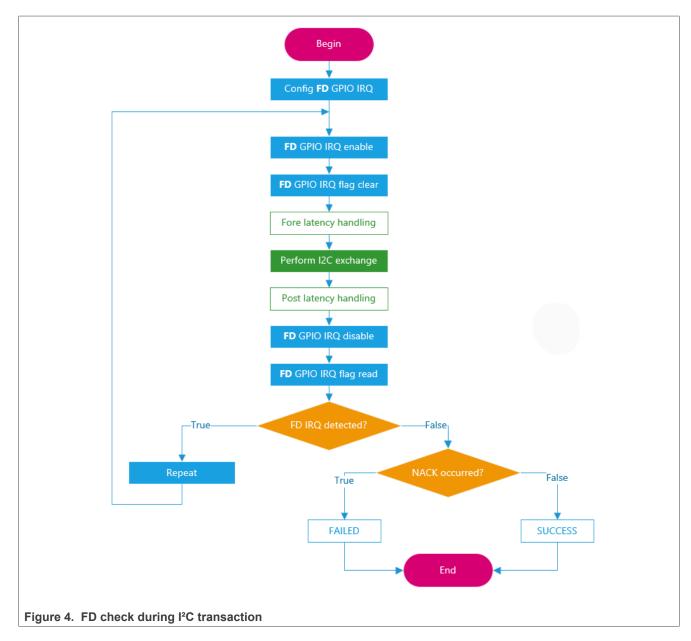
FD signal latency (time between FD pin toggle and real RF ON/OFF) must be considered, more details in chapter <u>Section 2.1.1.3.4</u>. Below <u>Figure 3</u> gives a visual representation (the timebase is not in scale).



2.1.1.3.3 Flow diagram of reliable I²C communication with FD pin monitoring from Host Controller

Flowchart in <u>Figure 4</u> is describing the steps to ensure reliable I²C communication, while monitoring RF field status using the FD pin from the Host MCU:

- 1. MCU Host initially configures and enables the FD GPIO IRQ for RF-ON and RF-OFF
- 2. MCU Host clears the FD GPIO IRQ
- 3. MCU Host waits for 20 µs and FD pin latency
- 4. Perform I2C transaction
- 5. MCU Host waits for 20 µs and FD pin latency
- 6. MCU Host disables and reads FD GPIO IRQ
- 7. Based on FD GPIO IRQ read, MCU Host takes a decision to finish or continue with the I²C transaction



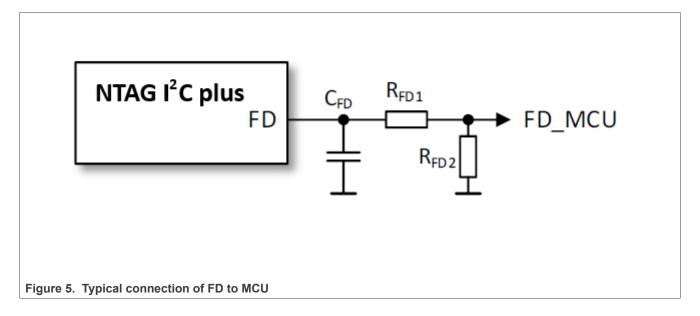
2.1.1.3.4 FD Pin and latency explanation

FD pin can be used to monitor NFC RF field presence.

On Figure 5 it is shown:

- Typical connection of FD pin to MCU (incl. voltage level conversion)
- FD toggling latency depends on the component values used

For more information about Field Detection Pin, refer to the data sheet.



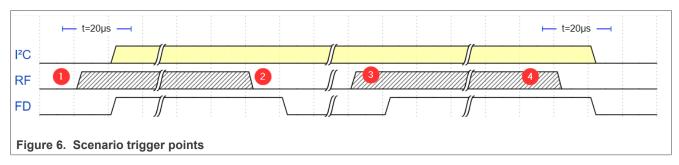
2.1.2 I2C Read/Write payload data not valid

2.1.2.1 Scenario description

NTAG I²C *plus* cannot send valid data to MCU Host or can skip I²C Write, when the RF-ON/RF-OFF event occurs during I²C Read and Write transactions.

This scenario can occur due to below points mentioned in <u>Figure 6</u>. It is a visual representation, without precise timings.

- 1. RF state change (RF-ON) occurs within a 20 µs window before the I²C transaction starts.
- 2. RF state change (RF-OFF) happens during an I²C transaction.
- 3. RF state change (RF-ON) happens during an I²C transaction.
- 4. RF state change (RF-OFF) happens within a 20 µs window after the I2C transaction concludes.



Note: The latency of FD pin at points 1, 2, 3, 4 depends on the decoupling capacitor value.

2.1.2.2 Scenario impact

EEPROM data coming from an I²C READ transaction (from NTAG I²C plus) may not be valid.

I²C write access might be skipped and still acknowledged.

2.1.2.3 Recommendations

Refer to <u>Section 2.3.7</u>. In general all recommendations from <u>Section 2.1.1.3</u> shall be considered.

2.2 NTAG I²C plus I²C address recovery mechanism

If NTAG I²C *plus* I²C follower address is corrupted, the following can be applied to recover the NTAG I²C *plus* I²C follower address.

2.2.1 NTAG I²C plus I²C address recovery procedure to any address between 0x00 to 0x7F

- 1. Scan for the address starting from 0x00 to 0x7F
- 2. Read a Block of NTAG I²C plus and verify for the status
- 3. Success shows the address of the device
- 4. With the obtained address, write back the original address of NTAG I²C *plus* in the Byte 0 of memory block 0x00
- 5. With the original address, perform the Read operation of the block for confirming the default address is written back properly

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2.3 Best practices for Host MCU SW

2.3.1 Verify the EEPROM WR BUSY Flag in EEPROM Write

- Once EEPROM Write started, the Application software shall use a HW timer for time counting, set up for 5
 ms
- 2. While the timer is running, the Application software checks for the EEPROM_WR_BUSY flag in the NS REG.
- 3. If it's cleared before the timer expired, the EEPROM write operation is finished, exit the loop.
- 4. In the case of timeout the Application software WRITE function returns an error flag, the Application software takes appropriate actions.
- 5. If the loop is exited before timeout (and the ERR flag isn't set), the WRITE operation completed successfully.

2.3.2 Use SESSION_REG to control and adjust NTAG I²C *plus* runtime settings

- 1. Content of CONFIG_REG copied into SESSION_REG at first RF_ON.
- 2. Content of CONFIG_REG is checked once per boot and modified if there are any wrong parameters (Can be Skipped if Configuration Register is LOCKED).
- 3. The Application software controls SESSION_REG for runtime settings of NTAG I²C *plus* [the Application software/application does not verify contents of SESSION_REG at boot].

2.3.3 Reset the I²C Arbitration Flag

- 1. Clear the I2C_LOCKED bit in the NS_REG after the common Application software functions where I2C communication is used.
- 2. Although the I2C_LOCKED flag will be released by WDT, the Application software does it manually to get back into the defined state and increase the speed of data flow.

2.3.4 Verify I²C communication timing parameters for 400kbits/s Fast Mode: SCL high and low time

- 1. SCL high time for fast mode must be greater than 950 ns.
- 2. SCL low time for fast mode must be greater than 1.3 μ s.

2.3.5 Lock CONFIG_REG

It is recommended to set the REG_LOCK byte to 0x03 as the last step of personalization.

Table 2. Configuration bytes

Bit	Field	Access via NFC	Access via I ² C	Default values	Description	
	Configuration register: REG_LOCK					
7-2	RFU	R&W	R&W	000000b	RFU - all 6-bits SHALL be 0b	
1	REG_LOCK_I2C ¹	R&W	R&W	0b	I ² C Configuration Lock Bit 0b: Configuration bytes may be changed via I ² C 1b: Configuration bytes cannot be changed via I ² C Once set to 1b, it cannot be reset to 0b anymore.	
0	REG_LOCK_NFC ¹	R&W	R&W	0b	NFC Configuration Lock Bit 0b: Configuration bytes may be changed via NFC 1b Configuration bytes cannot be changed via NFC Once set to 1b, it cannot be reset to 0b anymore.	

¹ Setting both bits REG_LOCK_I2C and REG_LOCK_NFC to 1b, permanently locks write-access to register default values (as no write is allowed anymore). As long as one bit is still 0b, the corresponding interface can still access and change the register lock bytes.

2.3.6 Data programming/writing verification

Verify if the data was programmed correctly in the following order:

- 1. I2C READ the data
- 2. store this data for later comparison
- 3. I2C WRITE new data
- 4. I2C READ newly programmed data
- 5. compare 2 fetched data sets and confirm the success of I²C WRITE operation

2.3.7 Data read verification

Verify if the data read has the correct values, comparing it to known values (for example, Configuration registers) in the following order:

- 1. I2C READ the data
- 2. Compare the data
- 3. if compared data has not match with expected values redo I2C Read once more

3 SCL and SDA glitch

3.1 Issue description

When powering NTAG I²C plus via V_{CC}, I²C lines are pulled low for a specific duration during startup only.



3.2 Issue impact

This glitch may be interpreted by other I²C targets on the same I²C bus as an I²C start condition. Ongoing I²C communication with other I²C targets may be disturbed.

3.3 Issue workaround

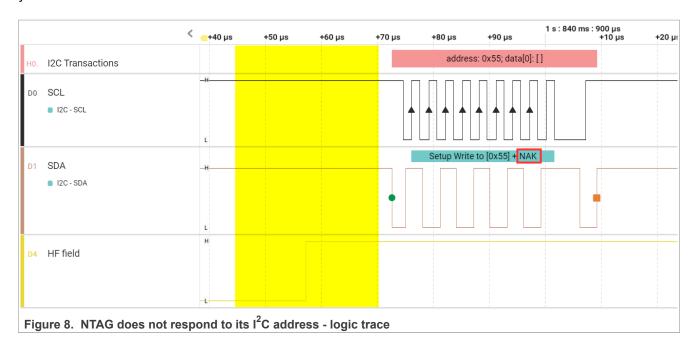
It is recommended to power up NTAG I^2C *plus* as the first I^2C target or simultaneously with other I^2C targets. Alternatively, there should be no communication with other I^2C targets during NTAG I^2C *plus* startup and any pulses shall be ignored for 1 ms.

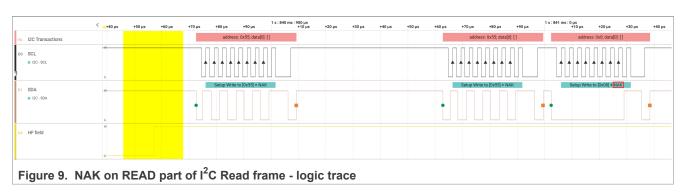
4 I²C target address NAK-ed

4.1 Issue description

- NTAG does not respond on its I²C address Figure 8
- or NAKs I²C address on read part <u>Figure 9</u>

if RF field turns ON in the time range between \sim 22 µs to 16 µs before I²C start condition as depicted below in yellow:





4.2 Issue impact

In applications, where the I²C controller device randomly accesses NTAG's user memory (EEPROM), NTAG may not respond to its I²C address anymore. I²C command retry, VCC reset, or RF reset is needed. The issue occurs at the time when RF goes ON within the exact time-window and the I²C command frame starts (START&STOP, no repeated start).

4.3 Issue workaround

1. Retry of I²C command frame



- 2. VCC reset
- 3. RF reset

The recovery mechanism shall be done in the above order as it can happen, that a simple I²C command retry will be sufficient.

Recommendation: The frequency of accessing NTAG's EEPROM from the I²C perspective shall be as low as possible. I²C controller device shall wait for events from the RF side and act later, to avoid accessing EEPROM consequently. This would give RF interface higher priority to EEPROM access over RF and would avoid simultaneous accessing.

NTAG I²C plus

5 References

[1] Data Sheet – NT3H2111_2211 – NTAG I²C *plus*: NFC Forum T2T with I²C interface, password protection and energy harvesting (<u>link</u>)

6 Revision history

Table 3. Revision history

Document ID	Release date	Description		
ES_NT3H2111_2211 v.4.1	30 October 2025	Document security status changed to "public". Editorial changes. Updated the term "NACK" to "NAK" throughout this document. • Section 5 "References": added.		
ES_NT3H2111_2211 v.4.0	20 March 2025	Editorial changes. Section 2 "I ² C Read command treated as I ² C Write command and I ² C Read/Write payload data not valid": added.		
ES_NT3H2111_2211 v.3.0	3 November 2023	Section 3 "SCL and SDA glitch": added.		
ES_NT3H2111_2211 v.2.0	31 October 2019	Section 4 "I2C target address NAK-ed": added.		

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